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# National Institute of Standards and Technology



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National Institute of Standards and Technology

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- Information Access and User Interfaces
- High Performance Systems and Services
- Distributed Computing and Information Services
- Software Diagnostics and Conformance Testing

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<sup>1</sup>At Boulder, CO 80303.

<sup>2</sup>Some elements at Boulder, CO.

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The *Journal of Research of the National Institute of Standards and Technology*, the flagship periodic publication of the national metrology institute of the United States, features advances in metrology and related fields of physical science, engineering, applied mathematics, statistics, and information technology that reflect the scientific and technical programs of the Institute. The *Journal* publishes papers on instrumentation for making accurate measurements, mathematical models of physical phenomena, including computational models, critical data, calibration techniques, well-characterized reference materials, and quality assurance programs that report the results of current NIST work in these areas. Occasionally, a Special Issue of the *Journal* is devoted to papers on a single topic. Also appearing on occasion are review articles and reports on conferences and workshops sponsored in whole or in part by NIST.

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### **In Memoriam**

**Dr. Chris E. Kuyatt of the Director's Office, and chairman of NIST's Washington Editorial Review Board (WERB) served with distinction as a member of the Board of Editors of the Journal of Research for the past 7 years. We are saddened by his recent death.**